

## CLAIMS

1. A probe station for probing a test device,  
said probe station comprising:

5 (a) a chuck for supporting said test device;

(b) a plurality of electrically conductive  
members, each electrically isolated from, and at least  
partially enclosing said surface; and

(c) a selector member having a plurality of  
10 positions, one said position electrically isolating said  
electrically conductive members from each other and  
another said position electrically interconnecting one  
said conductive member with at least one other said  
conductive member.

15 2. The probe station of claim 1 having only  
two said conductive members.

3. The probe station of claim 1 including an  
outer conductive member at least partially surrounding at  
least one other said conductive member.